



# CERTIFICATE OF ACCREDITATION

## The ANSI National Accreditation Board

Hereby attests that

**GD4 Test Services, Inc.**  
8000 Anderson Square, Suite 105  
Austin, TX 78757

(and satellites as listed on the scope)

Fulfills the requirements of

**ISO/IEC 17025:2017**  
and

**AS6171 Detection of Suspect/Counterfeit Parts Accreditation Program**

In the field of

**TESTING**

This certificate is valid only when accompanied by a current scope of accreditation document.  
The current scope of accreditation can be verified at [www.anab.org](http://www.anab.org).

R. Douglas Leonard Jr., VP, PILR SBU

Expiry Date: 29 July 2024  
Certificate Number: AT-2892



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017.  
This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).

**SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017  
and AS6171 Detection of Suspect/Counterfeit Parts Accreditation Program**

**GD4 Test Services, Inc.**  
8000 Anderson Square, Suite 105  
Austin, TX 78757  
George Jastroch [gj@gd4test.com](mailto:gj@gd4test.com)  
512 535 1677

**TESTING**

Valid to: **July 29, 2024**

Certificate Number: **AT-2892**

In recognition of a successful assessment to ISO/IEC 17025:2017 General Requirements for the competence of Testing and Calibration Laboratories, AS6171 General Requirements, and the requirements of the ANAB SR 2429 – Labs Performing Detection of Suspect/Counterfeit Parts Under AS6171 program, accreditation is granted to **GD4 Test Services, Inc.** to perform the following AS6171 slash sheet tests:

**Mechanical**

| Specific Tests and/or Properties Measured | Specification, Standard, Method, or Test Technique  | Items, Materials or Product Tested | Key Equipment or Technology      |
|---|---|------------------------------------|----------------------------------|
| Decapsulation                             | AS6081, Sect. 4.2.6.4.6, AS6171/4 Sect. 3.1 – 3.7   | Electronic Components              | Hotplate, Multiple Acids         |
| Heated Chemical Test                      | AS6081, Sect. 4.2.6.4.3, AS6171/2A, Sect. 5.3.4 Method D                                    |                                    | Multiple Chemicals               |
| X-Ray Inspection                          | AS6081, Sect. 4.2.6.4.4, AS6171/5   |                                    | Focal Spot X-Ray                 |
| XRF Inspection                            | AS6081, Sect. 4.2.6.4.5, AS6171/3   |                                    | Quickshot XRF                    |
| Temperature Cycle                         | MIL-STD-883K, Method 1010, AS6081 Sect. C.2   |                                    | Blue M Temperature Cycle Chamber |
| C-SAM                                     | AS6081, Sect. C.6   |                                    | OKOS Sonoscan                    |
| Visual Inspection                         | AS6081, Sect. 4.2.6.4.2, AS6171/2A, Method A and B (Excluding Weights), AS6171/2A, Method E |                                    | Multiple Scopes                  |
| Resistance to Solvents                    | AS6081, Sect. 4.2.6.4.3-A, AS6171/2A, Method C  |                                    | Multiple Chemicals               |

**Electrical**

| Specific Tests and/or Properties Measured  | Specification, Standard, Method, or Test Technique | Items, Materials or Product Tested | Key Equipment or Technology    |
|--|--|------------------------------------|--------------------------------|
| Electrical Test: Resistors, Capacitors, Inductors, Relays, connectors, Microcircuits and Semiconductor devices | AS6171/7 Table 2, AS6081, Sect. C.3                | Electronic Components              | Multiple A.T.E. Equipment Sets |



## SATELLITE SITE

### GD4 Test Services, Inc.

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Largo, FL 33773  
George Jastroch [gj@gd4test.com](mailto:gj@gd4test.com)  
512 535 1677

## TESTING

### Mechanical

| Specific Tests and/or Properties Measured | Specification, Standard, Method, or Test Technique  | Items, Materials or Product Tested | Key Equipment or Technology |
|---|---|------------------------------------|-----------------------------|
| Decapsulation                             | AS6081, Sect. 4.2.6.4.6, AS6171/4 Sect. 3.1 – 3.7   | Electronic Components              | Hotplate, Multiple Acids    |
| Heated Chemical Test                      | AS6081, Sect. 4.2.6.4.3, AS6171/2A, Sect. 5.3.4 Method D                                    |                                    | Multiple Chemicals          |
| X-Ray Inspection                          | AS6081, Sect. 4.2.6.4.4, AS6171/5   |                                    | Focal Spot X-Ray            |
| XRF Inspection                            | AS6081, Sect. 4.2.6.4.5, AS6171/3   |                                    | Quickshot XRF               |
| Visual Inspection                         | AS6081, Sect. 4.2.6.4.2, AS6171/2A, Method A and B (Excluding Weights), AS6171/2A, Method E |                                    | Multiple Scopes             |
| Resistance to Solvents                    | AS6081, Sect. 4.2.6.4.3-A, AS6171/2A, Method C  |                                    | Multiple Chemicals          |

### Electrical

| Specific Tests and/or Properties Measured | Specification, Standard, Method, or Test Technique | Items, Materials or Product Tested | Key Equipment or Technology    |
|---|--|------------------------------------|--------------------------------|
| Electrical Test                           | AS6171/7<br>AS6081 – C.3                           |                                    | Multiple A.T.E. Equipment Sets |

## SATELLITE SITE

### GD4 Test Services, Inc.

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512 535 1677

## TESTING

### Mechanical

| Specific Tests and/or Properties Measured | Specification, Standard, Method, or Test Technique  | Items, Materials or Product Tested | Key Equipment or Technology |
|---|---|------------------------------------|-----------------------------|
| Decapsulation                             | AS6081, Sect. 4.2.6.4.6, AS6171/4 Sect. 3.1 – 3.7   | Electronic Components              | Hotplate, Multiple Acids    |
| Heated Chemical Test                      | AS6081, Sect. 4.2.6.4.3, AS6171/2A, Sect. 5.3.4 Method D                                    |                                    | Multiple Chemicals          |
| X-Ray Inspection                          | AS6081, Sect. 4.2.6.4.4, AS6171/5   |                                    | Focal Spot X-Ray            |
| XRF Inspection                            | AS6081, Sect. 4.2.6.4.5, AS6171/3   |                                    | Quickshot XRF               |
| Visual Inspection                         | AS6081, Sect. 4.2.6.4.2, AS6171/2A, Method A and B (Excluding Weights), AS6171/2A, Method E |                                    | Multiple Scopes             |
| Resistance to Solvents                    | AS6081, Sect. 4.2.6.4.3-A, AS6171/2A, Method C  |                                    | Multiple Chemicals          |

### Electrical

| Specific Tests and/or Properties Measured  | Specification, Standard, Method, or Test Technique | Items, Materials or Product Tested | Key Equipment or Technology    |
|--|--|------------------------------------|--------------------------------|
| Electrical Test: Resistors, Capacitors, Inductors, Relays, connectors, Microcircuits and Semiconductor devices | AS6171/7 Table 2, AS6081, Sect. C.3                | Electronic Components              | Multiple A.T.E. Equipment Sets |

Note:

1. This scope is formatted as part of a single document including Certificate of Accreditation No. AT-2892.



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